

## MTBF Confidence Limits

When a product's failure rate is considered constant, The Chi-Square distribution may be used to calculate confidence intervals around a measured mean time between failures (MTBF), the total test time among all tested products divided by the number of failures. The calculation differs depending on whether the test data truncates on the last failure or at a time after the last failure. The formulas used are:

	For time truncated tests		For failure truncated tests	
One-sided Confidence interval (MTBF lower limit)	$\frac{2T}{\chi^2(\alpha, 2n + 2)}$		$\frac{2T}{\chi^2(\alpha, 2n)}$	
Two-sided Confidence intervals	$\frac{2T}{\chi^2(\alpha/2, 2n + 2)}$	$\frac{2T}{\chi^2(1 - \alpha/2, 2n)}$	$\frac{2T}{\chi^2(\alpha/2, 2n)}$	$\frac{2T}{\chi^2(1 - \alpha/2, 2n)}$
MTBF limit:	Lower	Upper	Lower	Upper

Where T is the total test time

$\alpha$  is the acceptable risk of error (1- desired confidence)

n is the number of failures observed

The following table is derived from the formulas: <http://www.kekaoxing.com>

### (Assumption of Exponential Distribution)

d	<div><div><div>99% Two-Sided</div><div>99-1/2% One-Sided</div></div><div><div>98% Two-Sided</div><div>99% One-Sided</div></div><div><div>95% Two-Sided</div><div>97-1/2% One-Sided</div></div><div><div>90% Two-Sided</div><div>95% One-Sided</div></div><div><div>80% Two-Sided</div><div>90% One-Sided</div></div><div><div>60% Two-Sided</div><div>80% One-Sided</div></div></div>												
	Lower Limit						Upper Limit						
	2	0.185	0.217	0.272	0.333	0.433	0.619	4.47	9.462	19.388	39.58	100.0	200.0
	4	0.135	0.151	0.180	0.210	0.257	0.334	1.21	1.882	2.826	4.102	6.667	10.00
	6	0.108	0.119	0.139	0.159	0.188	0.234	0.652	0.909	1.221	1.613	2.3077	3.007
	8	0.0909	0.100	0.114	0.129	0.150	0.181	0.437	0.573	0.733	0.921	1.212	1.481
10	0.0800	0.0857	0.0976	0.109	0.125	0.149	0.324	0.411	0.508	0.600	0.789	0.909	
12	0.0702	0.0759	0.0856	0.0952	0.107	0.126	0.256	0.317	0.383	0.454	0.555	0.645	
14	0.0635	0.0690	0.0765	0.0843	0.0948	0.109	0.211	0.257	0.305	0.355	0.431	0.500	
16	0.0588	0.0625	0.0693	0.0760	0.0848	0.0976	0.179	0.215	0.251	0.290	0.345	0.385	
18	0.0536	0.0571	0.0633	0.0693	0.0769	0.0878	0.156	0.184	0.213	0.243	0.286	0.322	
20	0.0500	0.0531	0.0585	0.0635	0.0703	0.0799	0.137	0.158	0.184	0.208	0.242	0.270	
22	0.0465	0.0495	0.0543	0.0589	0.0648	0.0732	0.123	0.142	0.162	0.182	0.208	0.232	
24	0.0439	0.0463	0.0507	0.0548	0.0601	0.0676	0.111	0.128	0.144	0.161	0.185	0.200	
26	0.0417	0.0438	0.0476	0.0513	0.0561	0.0629	0.101	0.116	0.130	0.144	0.164	0.178	
28	0.0392	0.0413	0.0449	0.0483	0.0527	0.0588	0.0927	0.106	0.118	0.131	0.147	0.161	
30	0.0373	0.0393	0.0425	0.0456	0.0496	0.0551	0.0856	0.0971	0.108	0.119	0.133	0.145	
32	0.0355	0.0374	0.0404	0.0433	0.0469	0.0519	0.0795	0.0899	0.0997	0.109	0.122	0.131	
34	0.0339	0.0357	0.0385	0.0411	0.0445	0.0491	0.0742	0.0834	0.0925	0.101	0.113	0.122	
36	0.0325	0.0342	0.0367	0.0392	0.0423	0.0466	0.0696	0.0781	0.0899	0.0939	0.104	0.111	
38	0.0311	0.0327	0.0351	0.0375	0.0404	0.0443	0.0656	0.0732	0.0804	0.0874	0.0971	0.103	
40	0.0299	0.0314	0.0337	0.0359	0.0386	0.0423	0.0619	0.0689	0.0756	0.0820	0.0901	0.0968	



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- Notes:**
1. Multiply value shown by total part hours to get MTBF figure in hours.
  2.  $d = 2 \times (\text{\# of failures accumulated at test termination})$ .
  3. For the lower limit on tests truncated at a fixed time where the number of failures occurring is less than the total number of items placed on test initially, use:  $d = 2 \times (\text{\# of failures accumulated at test termination} + 1)$ .

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**Source:**

- RAC Publication, CPE, Reliability Toolkit: Commercial Practices Edition.

**For More Information:**

- RAC Publication, STAT, Practical Statistical Tools for the Reliability Engineer, Sept. 1999.

<http://www.kekaoxing.com> <http://www.kekaoxing.com/club/>

